

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 09/657,685 | Applicant(s)/Patent Under Reexamination KRSTANOVSKI ET AL. | |
| | Examiner Clemence Han | Art Unit 2665 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-5,793,771 | 08-1998 | Darland et al. | 370/467 |
| | B | US-2002/0085512 | 07-2002 | Lehtimaki et al. | 370/328 |
| | C | US-5,579,316 | 11-1996 | Venters et al. | 370/392 |
| | D | US-5,978,386 | 11-1999 | Hamalainen et al. | 370/466 |
| | E | US-6,233,458 | 05-2001 | Haumont et al. | 455/445 |
| | F | US-6,377,804 | 04-2002 | Lintulampi, Raino | 455/435.2 |
| | G | US-6,542,516 | 04-2003 | Vialen et al. | 370/465 |
| | H | US-6,584,098 | 06-2003 | Dutnall, Stephen | 370/354 |
| | I | US-6,594,486 | 07-2003 | Rasanen, Juha | 455/422.1 |
| | J | US-6,658,011 | 12-2003 | Sevanto et al. | 370/401 |
| | K | US-2002/0086667 | 07-2002 | Suvarnen, Jyri | 455/422 |
| | L | US-2002/0155825 | 10-2002 | Haumont et al. | 455/412 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|-----------------|-----------------|----------------|
| | N | EP 1079655 A1 | 02-2001 | European Patent | PALAT et al. | H04Q 07/38 |
| | O | EP 1079643 A1 | 02-2001 | European Patent | CASATI, ALESSIO | H04Q 07/22 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.